

March 2007

FDMA1023PZ

Dual P-Channel PowerTrench® MOSFET

-20V, -3.7A, 72mΩ

Features

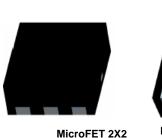
- Max $r_{DS(on)} = 72m\Omega$ at $V_{GS} = -4.5V$, $I_D = -3.7A$
- Max $r_{DS(on)} = 95m\Omega$ at $V_{GS} = -2.5V$, $I_D = -3.2A$
- Max $r_{DS(on)} = 130m\Omega$ at $V_{GS} = -1.8V$, $I_D = -2.0A$
- Max $r_{DS(on)} = 195m\Omega$ at $V_{GS} = -1.5V$, $I_D = -1.0A$
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- RoHS Compliant

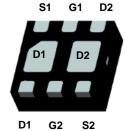


General Description

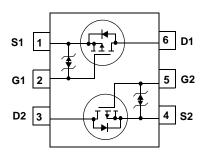
This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultraportable applications. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. When connected in the typical common source configuration, bi-directional current flow is possible.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.





Pin 1



MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	V _{DS} Drain to Source Voltage		-20	V
V _{GS}	Gate to Source Voltage		±8	V
I _D	Drain Current -Continuous	(Note 1a)	-3.7	^
	-Pulsed		-6	A
Б	Power Dissipation	(Note 1a)	1.5	10/
P _D		(Note 1b)	0.7	W
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1b)	173	°C/W
$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1c)	69	- C/VV
$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1d)	151	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
023	FDMA1023PZ	MicroFET 2X2	7"	8mm	3000 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		-11		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16V, \ V_{GS} = 0V$			-1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8V$, $V_{DS} = 0V$			±10	μА

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		2.5		mV/°C
		$V_{GS} = -4.5V$, $I_D = -3.7A$		60	72	
		$V_{GS} = -2.5V$, $I_D = -3.2A$		75	95	
r _{DS(on)}	Static Drain to Source On-Resistance	$V_{GS} = -1.8V$, $I_D = -2.0A$		100	130	mΩ
, ,		$V_{GS} = -1.5V$, $I_D = -1.0A$		130	195	
		$V_{GS} = -4.5V$, $I_D = -3.7A$, $T_J = 125$ °C		81	91	
9 _{FS}	Forward Transconductance	$V_{DS} = -5V, I_{D} = -3.7A$		12		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40V V 0V	490	655	pF
C _{oss}	Output Capacitance	$V_{DS} = -10V, V_{GS} = 0V,$ $f = 1MHz$	100	135	pF
C _{rss}	Reverse Transfer Capacitance	1 - 117112	90	135	pF

Switching Characteristics

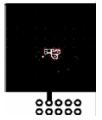
t _{d(on)}	Turn-On Delay Time	.,	9	18	ns
t _r	Rise Time	$V_{DD} = -10V, I_{D} = -1A$ $V_{GS} = -4.5V, R_{GEN} = 6\Omega$	12	22	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5V, R_{GEN} = 602$	64	103	ns
t _f	Fall Time		37	60	ns
$Q_{g(TOT)}$	Total Gate Charge	$V_{DD} = -10V, I_D = -3.7A$	8.6	12	nC
Q _{gs}	Gate to Source Gate Charge	$V_{GS} = -4.5V$	0.7		nC
Q_{gd}	Gate to Drain "Miller" Charge		2.0		nC

Drain-Source Diode Characteristics

Is	Maximum Continuous Drain-Source Diode Forward Current				-1.1	Α
V_{SD}	Source to Drain Diode Forward Voltage $V_{GS} = 0V$, $I_S = -1.1A$ (Note 2)			-0.8	-1.2	V
t _{rr}	Reverse Recovery Time I _E = -3.7A, di/dt = 100A/µs			32	48	ns
Q _{rr}	Reverse Recovery Charge	$_{\text{IF}} = -3.7 \text{A}, \text{ di/dt} = 100 \text{A/} \mu\text{S}$		15	23	nC

Notes:

- 1. R_{θ,JA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{θ,JC} is guaranteed by design while R_{θ,JA} is determined by the user's board design.
 - (a) $R_{\theta JA} = 86^{\circ}\text{C/W}$ when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (b) $R_{\theta JA}$ = 173°C/W when mounted on a minimum pad of 2 oz copper
 - (c) $R_{\theta JA} = 69^{o}$ C/W when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB.
 - (d) $R_{\theta JA} = 151^{\circ}\text{C/W}$ when mounted on a minimum pad of 2 oz copper.



a)86°C/W when mounted on a 1in² pad of 2 oz copper.



b)173°C/W when mounted on a minimum pad of 2 oz copper.



c)69°C/W when mounted on a 1in² pad of 2 oz copper.



d)151°C/W when mounted on a minimum pad of 2 oz copper.

2: Pulse Test : Pulse Width < 300us, Duty Cycle < 2.0%

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

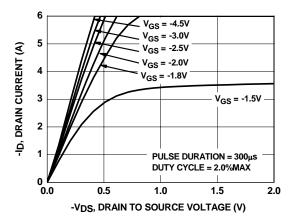


Figure 1. On Region Characteristics

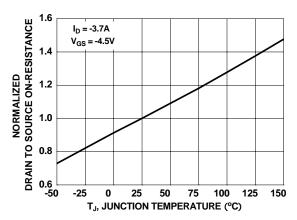


Figure 3. Normalized On-Resistance vs Junction Temperature

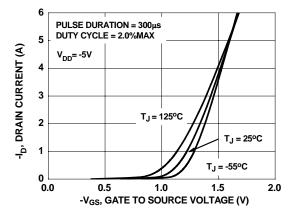


Figure 5. Transfer Characteristics

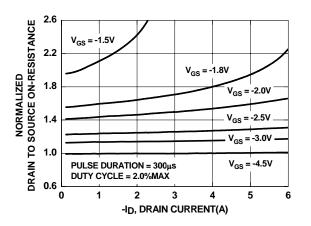


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

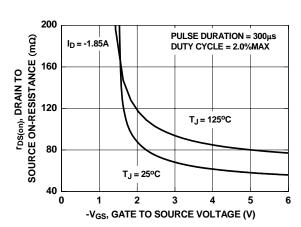


Figure 4. On-Resistance vs Gate to Source Voltage

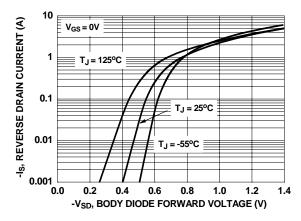


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

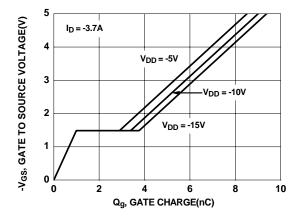


Figure 7. Gate Charge Characteristics

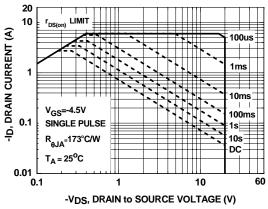


Figure 9. Forward Bias Safe Operating Area

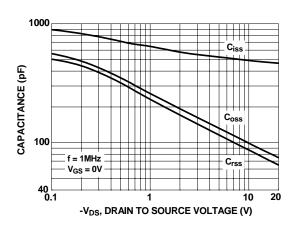


Figure 8. Capacitance Characteristics

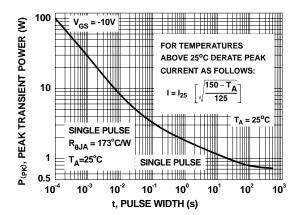


Figure 10. Single Pulse Maximum Power Dissipation

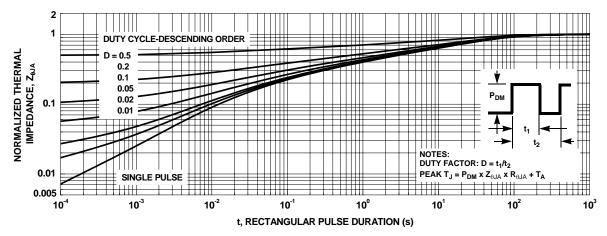
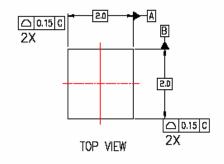
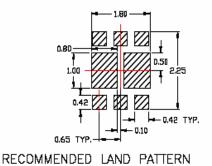
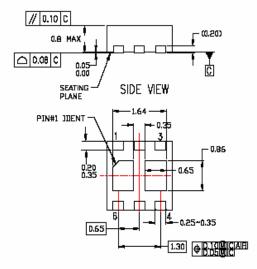


Figure 11. Transient Thermal Response Curve







BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC, DATED 11/2001
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

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